Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/565,233 .	CROTEAU ET AL.		
Examiner	Art Unit		
Yong D. Pak	1652		

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
stic: seq id no: 1 and 2	9/27/2007	ΥP	
east: text and inventor search, see search history	9/27/2007	ΥP	
PALM: inventor search, all inventors	9/27/2007	ΥP	
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